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Four Channel Load-Switch / LDO Configurable PMIC

FAN53840, FAN53841

General Description

The FAN53840 family are low Iq PMICs intended for mobile power application camera modules. The PMIC contains a high−power regulated channel for digital rails which can operate with an input as low as 1.0 V. Three channels are designed for ultra−low noise and high PSRR for sensitive analog/RF circuit loads. Each channel can be configured to operate as a pass−through load−switch, which reduces the input to output voltage drop and operating currents in critical low power applications.

The device is available in 16−bump, 0.35 mm pitch, Wafer−Level Chip−Scale Package (WLCSP).

Features

- LDO1:
	- ♦ 1.2 A Output Current Capability
	- ♦ Programmable Output Voltage 0.8 V to 1.504 V in 8 mV Steps
	- 1.0 V to 2.0 V Input Voltage Range
	- \cdot 1.1% to -1.5% Accuracy
- LDO2, LDO3, and LDO4:
	- ♦ 300 mA Output Current Capability
	- ♦ Programmable Output Voltage 1.5 V to 3.412 V in 8 mV Steps
	- 1.9 V to 5.5 V Input Voltage Range
	- \triangleleft Less than 20 µV (typ) Noise
- Load−Switch Operation:
	- $\rightarrow 100/200$ m Ω Maximum Channel Resistance
	- Low Operating Currents
	- ♦ Input Voltages Down to 1.0 V and 1.8 V
- Operation Guaranteed with System Voltage Down to 2.6 V
- Soft−Start Function (SS) to Limit Inrush Current
- Current Limit to Protect Against Short Circuit
- I ²C Protection Fault (UVLO and OCP in LDO Operation) Registers
- I ²C Serial Control to Program Output Voltage and Features
- System UVLO and Thermal Global Shutdown Protection for LDOs
- Pb−Free Devices

Applications

- Smart Phones
- Wearables
- Smart Watch
- Health Monitoring
- Sensor Drive
- Energy Harvesting
- Utility and Safety Modules
- RF Modules

WLCSP16 1.52x1.52x0.432 CASE 567ZM

MARKING DIAGRAM

-
- Y = 2-weeks Date Code
Z = Assembly Plant Code = Assembly Plant Code
-

ORDERING INFORMATION

See detailed ordering and shipping information on page [2](#page-1-0) of this data sheet.

ORDERING INFORMATION

ÜFor information on tape and reel specifications, including part orientation and tape sizes, please refer to our Tape and Reel Packaging Specifications Brochure, <u>BRD8011/D</u>.

1. RESET_B, SDA, SCL (open drain type pins)

2. I2C address is configurable. See I2C section for more information on setting the device address

APPLICATION CIRCUIT

Application Circuit Diagram

Figure 2. Load Switch Mode

Application Circuit Components

PRODUCT PIN ASSIGNMENTS

Table 1. RECOMMENDED EXTERNAL COMPONENTS

Top View (Bumps Down) and Top View (Bumps Up)

Figure 3. Pin Configuration

PIN DEFINITIONS

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PRODUCT BLOCK DIAGRAM

Block Diagram

Figure 4. Block Diagram

MAXIMUM RATINGS

Stresses exceeding those listed in the Maximum Ratings table may damage the device. If any of these limits are exceeded, device functionality should not be assumed, damage may occur and reliability may be affected.

THERMAL CHARACTERISTICS

RECOMMENDED OPERATING CONDITIONS

Functional operation above the stresses listed in the Recommended Operating Ranges is not implied. Extended exposure to stresses beyond the Recommended Operating Ranges limits may affect device reliability.

3. Please refer to the Under Voltage Lockout (UVLO) section in Device Operation for details.

ELECTRICAL CHARACTERISTICS

Unless otherwise noted, the device is characterized for minimums and maximums across the ranges listed in the Recommended Operating Conditions. All limits are characterized using components from Recommended External Components table.

Production testing and testing for typical values is performed at $T_A = 25^\circ C$, For LDO Mode: $V_{VSYS} = 3.45 V$, $V_{VIN1} = 1.3 V$, $V_{VIN2} = 3.45$ V, V_{VIN3} and $V_{VIN4} = 1.95$ V; For LS Mode: $V_{VSYS} = 3.80$ V, $V_{VIN1} = V_{VIN3} = V_{VIN4} = 1.8$ V and $V_{VIN2} = 5.0$ V.

CHANNEL 1 OUTPUT VOLTAGE

l_{VIN1} currents when all
LDO_LSx_SELECT = 1, $CHA\overline{N}1$ $E\overline{N}$ = 1 and all other channels are disabled.

 μA

CHANNEL 1 DRAIN−SOURCE ON RESISTANCE

CHANNEL 1 CURRENT LIMIT

ELECTRICAL CHARACTERISTICS (continued)

Unless otherwise noted, the device is characterized for minimums and maximums across the ranges listed in the Recommended Operating Conditions. All limits are characterized using components from Recommended External Components table.

Production testing and testing for typical values is performed at $T_A = 25^\circ C$, For LDO Mode: V_{VSYS} = 3.45 V, V_{VIN1} = 1.3 V, $V_{VIN2} = 3.45$ V, V_{VIN3} and $V_{VIN4} = 1.95$ V; For LS Mode: $V_{VSYS} = 3.80$ V, $V_{VIN1} = V_{VIN3} = V_{VIN4} = 1.8$ V and $V_{VIN2} = 5.0$ V.

ELECTRICAL CHARACTERISTICS (continued)

Unless otherwise noted, the device is characterized for minimums and maximums across the ranges listed in the Recommended Operating Conditions. All limits are characterized using components from Recommended External Components table.

Production testing and testing for typical values is performed at $T_A = 25^\circ C$, For LDO Mode: $V_{VSYS} = 3.45 V$, $V_{VIN1} = 1.3 V$, $V_{VIN2} = 3.45$ V, V_{VIN3} and $V_{VIN4} = 1.95$ V; For LS Mode: $V_{VSYS} = 3.80$ V, $V_{VIN1} = V_{VIN3} = V_{VIN4} = 1.8$ V and $V_{VIN2} = 5.0$ V.

ELECTRICAL CHARACTERISTICS (continued)

Unless otherwise noted, the device is characterized for minimums and maximums across the ranges listed in the Recommended Operating Conditions. All limits are characterized using components from Recommended External Components table.

Production testing and testing for typical values is performed at $T_A = 25^\circ C$, For LDO Mode: $V_{VSYS} = 3.45 V$, $V_{VIN1} = 1.3 V$, V_{VIN2} = 3.45 V, V_{VIN3} and V_{VIN4} = 1.95 V; For LS Mode: V_{VSYS} = 3.80 V, V_{VIN1} = V_{VIN3} = V_{VIN4} = 1.8 V and V_{VIN2} = 5.0 V.

Product parametric performance is indicated in the Electrical Characteristics for the listed test conditions, unless otherwise noted. Product performance may not be indicated by the Electrical Characteristics if operated under different conditions.

4. $\,$ LDOx Dropout Voltage is measured by lowering V $_{\rm VINx}$ until V $_{\rm OUTx}$ = VOUT_TARGET – 50 mV.

5. Total I_{VSYS}, I_{VIN1}, I_{VIN2}, I_{VIN3}, and I_{VIN4} when RESET_B = High, all CHANx_EN = 1, and all LDO_LSx_SELECT = 0.

6. $\,$ Total I $_{\rm VSYS}$, I $_{\rm VIN1}$, I $_{\rm VIN2}$, I $_{\rm VIN3}$, and I $_{\rm VIN4}$ when ${\rm REST_B}$ = High, all CHANx_EN = 1, and all LDO_LSx_SELECT = 1.

7. Total I_{VSYS}, I_{VIN1}, I_{VIN2}, I_{VIN3}, and I_{VIN4} when RESET_B = High, SCL = SDA = Low, all CHANx_EN = 0, and all LDO_LSx_SELECT = 0.

8. Total I_{VSYS}, I_{VIN1}, I_{VIN2}, I_{VIN3}, and I_{VIN4} when RESET_B = High, SCL = SDA = Low, all CHANx_EN = 0, and all LDO_LSx_SELECT = 1.

Guarantee Levels:

*Guaranteed by Design Only. Not Characterized or Production Tested.

SYSTEM CHARACTERISTICS

Unless otherwise noted, the device is characterized for minimums and maximums across the ranges listed in the Recommended Operating Conditions. All limits are characterized using components from Recommended External Components table.

Production testing and testing for typical values is performed at $T_A = 25^\circ C$, For LDO Mode: $V_{VSYS} = 3.45 V$, $V_{VIN1} = 1.3 V$, V_{VIN2} = 3.45 V, V_{VIN3} and V_{VIN4} = 1.95 V; For LS Mode: V_{VSYS} = 3.80 V, V_{VIN1} = V_{VIN3} = V_{VIN4} = 1.8 V and V_{VIN2} = 5.0 V.

CHANNEL 1 PSRR & NOISE

CHANNEL 1 REGULATION & TRANSIENT PERFORMANCE

CHANNEL 2 STARTUP

CHANNEL 2 PSRR & NOISE

CHANNEL 2 REGULATION & TRANSIENT PERFORMANCE

SYSTEM CHARACTERISTICS (continued)

Unless otherwise noted, the device is characterized for minimums and maximums across the ranges listed in the Recommended Operating Conditions. All limits are characterized using components from Recommended External Components table.

Production testing and testing for typical values is performed at $T_A = 25^\circ C$, For LDO Mode: $V_{VSYS} = 3.45 V$, $V_{VIN1} = 1.3 V$, V_{VIN2} = 3.45 V, V_{VIN3} and V_{VIN4} = 1.95 V; For LS Mode: V_{VSYS} = 3.80 V, V_{VIN1} = V_{VIN3} = V_{VIN4} = 1.8 V and V_{VIN2} = 5.0 V.

CHANNEL 4 STARTUP

 $V_{VIN3} \ge V_{OUT3} + 200$ mV, $\rm V_{OUT3}$ = 1.5 to 3.4 $\rm V$

CHANNEL 4 PSRR & NOISE

SYSTEM CHARACTERISTICS (continued)

Unless otherwise noted, the device is characterized for minimums and maximums across the ranges listed in the Recommended Operating Conditions. All limits are characterized using components from Recommended External Components table.

Production testing and testing for typical values is performed at $T_A = 25^\circ C$, For LDO Mode: V_{VSYS} = 3.45 V, V_{VIN1} = 1.3 V, $V_{VIN2} = 3.45$ V, V_{VIN3} and $V_{VIN4} = 1.95$ V; For LS Mode: $V_{VSYS} = 3.80$ V, $V_{VIN1} = V_{VIN3} = V_{VIN4} = 1.8$ V and $V_{VIN2} = 5.0$ V.

THERMAL PROTECTION

9. V_{VIN1} = 1.3 V, V_{VSYS} = 3.45 V, V_{OUT1} = 1.2 V, I_{OUT1} = 150 mA, C_{VIN1} = 1.0 μ F, C_{LDO1} = 10 μ F.

 $10. V_{VIN2} = 3.45 V, V_{VSYS} = 3.45 V, V_{OUT2} = 2.85 V, I_{OUT2} = 100 mA, C_{VIN2} = 1.0 \mu F, C_{LDO2} = 2.2 \mu F.$

11. V_{VIN3} = 1.95 V, V_{VSYS} = 3.45 V, V_{OUT3} = 1.8 V, I_{OUT3} = 100 mA, C_{VIN3} = 1.0 μ F, C_{LDOS} = 2.2 μ F.

 $12. V_{VIN4} = 1.95 V, V_{VSYS} = 3.45 V, V_{OUT4} = 1.8 V, I_{OUT4} = 100 mA, C_{VIN4} = 1.0 µF, C_{LDO4} = 2.2 µF.$

TYPICAL CHARACTERISTICS

(Unless otherwise noted, $T_A = 25^{\circ}$ C, For LDO Mode: $V_{VSYS} = 3.45$ V, $V_{VIN1} = 1.3$ V, $V_{VIN2} = 3.45$ V, V_{VIN3} and $V_{VIN4} = 1.95$ V; For LS Mode: V_{VSYS} = 3.80 V, V_{VIN1} = V_{VIN3} = V_{VIN4} = 1.8 V and V_{VIN2} = 5.0 V. Using components from Recommended External Components.)

Figure 7. LDO2 Output Voltage Accuracy vs. Load Current and Input Voltage, V_{OUT2} = 2.85 V

Figure 9. LDO1 Output Voltage Accuracy vs. Input and System Voltage, V_{OUT1} = 1.2 V and $I_{\text{OUT1}} = 50 \text{ mA}$

Figure 6. LDO1 Output Voltage Accuracy vs. Load Current and Input Voltage, V_{OUT1} = 1.2 V

Figure 8. LDO3/4 Output Voltage Accuracy vs. Load Current and Input Voltage, V_{OUT3/4} = 1.8 V

TYPICAL CHARACTERISTICS (continued)

(Unless otherwise noted, $T_A = 25^{\circ}$ C, For LDO Mode: $V_{VSYS} = 3.45$ V, $V_{VIN1} = 1.3$ V, $V_{VIN2} = 3.45$ V, V_{VIN3} and $V_{VIN4} = 1.95$ V; For LS Mode: $V_{VSYS} = 3.80 V$, $V_{VIN1} = V_{VIN3} = V_{VIN4} = 1.8 V$ and $V_{VIN2} = 5.0 V$. Using components from Recommended External Components.)

Figure 13. LS1 Quiescent Current vs. Input Voltage and Temperature

Figure 15. LS3/4 Quiescent Current vs. Input Voltage and Temperature

Figure 12. LDO3/4 Output Voltage Accuracy vs. Input and Output Voltage, $I_{\text{OUT3/4}} = 50 \text{ mA}$

Figure 14. LS2 Quiescent Current vs. Input Voltage and Temperature

TYPICAL CHARACTERISTICS (continued)

(Unless otherwise noted, $T_A = 25^\circ$ C, For LDO Mode: $V_{VSYS} = 3.45$ V, $V_{VIN1} = 1.3$ V, $V_{VIN2} = 3.45$ V, V_{VIN3} and $V_{VIN4} = 1.95$ V; For LS Mode: $V_{VSYS} = 3.80 V$, $V_{VINI1} = V_{VIN3} = V_{VIN4} = 1.8 V$ and $V_{VIN2} = 5.0 V$. Using components from Recommended External Components.)

Figure 16. LDO1 Load Transient, V_{VSYS} = 3.45 V, VVIN1 = 1.4 V, VOUT1 = 1.2 V, 1 mA <−> 1000 mA, 6 -s Edge

Figure 18. LDO3/4 Load Transient, V_{VSYS} = 3.45 V, $V_{VIN3/4}$ = 2.0 V, $V_{OUT3/4}$ = 1.8 V, **1 mA <−> 300 mA, 6 -s Edge**

Figure 17. LDO2 Load Transient, V_{VSYS} = 3.45 V, VVIN2 = 3.45 V, VOUT2 = 2.85 V, 1 mA <−> 300 mA, 6 -s Edge

TYPICAL CHARACTERISTICS (continued)

(Unless otherwise noted, $T_A = 25^{\circ}$ C, For LDO Mode: $V_{VSYS} = 3.45$ V, $V_{VIN1} = 1.3$ V, $V_{VIN2} = 3.45$ V, V_{VIN3} and $V_{VIN4} = 1.95$ V; For LS Mode: $V_{VSYS} = 3.80 V$, $V_{VIN1} = V_{VIN3} = V_{VIN4} = 1.8 V$ and $V_{VIN2} = 5.0 V$. Using components from Recommended External Components.)

FUNCTIONAL SPECIFICATIONS

Device Operation

Overview

The FAN53840 PMIC is optimized to supply different sub systems of battery powered mobile and IoT applications. It integrates four channels that can be set to operate as LDOs or Load−Switches (LS). The LDOs are low−dropout regulators: one high−current and three high PSRR/low noise LDOs. The LS are very low $R_{DS(0n)}$ and operate at low currents.

The features of the FAN53840 can be programmed through an $I²C$ interface.

Under Voltage Lockout (UVLO)

The device features system and LDO UVLO protections. When all channels are not selected as LDOs and LS, if the system voltage (V_{sys}) falls below its UVLO falling threshold, system UVLO interrupt and status bits will be set and INT_B asserted low. The status bit will remain set until V_{sys} rises above its UVLO rising threshold. If all LS are selected (By selecting all ldo lsx bits), no bits will be set; selecting all LS disables system UVLO protection faults. In this state it is possible to operate the four load−switches with their V_{IN} below the range stated in the Recommended Operating Conditions table. This is likely to increase LS RDS_{ON2} and therefore output current derating should be expected.

When enabling LDOs, if V_{sys} is above the Power On Reset (POR) voltage of 2 V but below its UVLO rising threshold, or, if V_{sys} is above its UVLO rising threshold but LDO input voltages are below their UVLO rising thresholds, corresponding UVLO interrupt and status bits will be set and INT_B asserted low. The status bits remain set as long the UVLO fault condition is present.

Similarly, bits and INT_B will be set and asserted low, respectively, when V_{sys} falls below its UVLO falling threshold and channels are not all configured as LS , or, V_{sys} is above its UVLO rising threshold but LDO input voltages fall below their UVLO falling threshold.

In the cases above, the LDOs will not be restarted for a minimum of 20ms and until V_{sys} rises above its rising threshold. Individual LDOs are permanently disabled after four cumulative faults including UVLO faults. The LDOs need to be enabled to return to operation. If the four cumulative faults are a combination of thermal−shutdown and system UVLO faults, then prior to enabling the LDOs, RESET B pin needs to be toggled from low to high.

Thermal Management

When the die temperature rises to the Thermal Warning (TWRN) threshold, interrupt and status bits indicating thermal−warning are set and INT_B asserted low. The status bit remains set until the die temperature drops to a nominal 105°C.

If the die temperature continues to rise to the Thermal Shutdown threshold, interrupt and status bits indicating thermal−shutdown will be set and INT_B asserted low. All

channels will be disabled but $I²C$ communication will remain. The status bit will remain set until the die temperature drops to T_{WRN} . The chip suspension bit is set upon shutdown.

After the die temperature falls below T_{WRN} , the thermal status and chip suspension bits will be cleared, and the device will return to the operating conditions prior to the thermal−shutdown event. Individual LDOs are permanently disabled after four cumulative faults including thermal faults. If the four cumulative faults are a combination of thermal−shutdown and system UVLO faults, then prior to enabling the LDOs, RESET B pin needs to be toggled from low to high.

Similarly to system UVLO, selecting all LS will render thermal protection faults inactive.

Enabling/Disabling

The channels can be enabled and disabled independently with the ldox en bits. To enable LDOs, with RESET B set high, select desired ldo*x*_en bits while setting *all* ldo_ls*x* bits to "0". The LDOs have internal soft–start which limits the inrush current to the current−limit setting of the LDO. The LDOs will ignore faults during the first 1.5 ms while starting−up.

To enable LS, with RESET_B set high, select desired ldox en bits while setting *all* ldo lsx bits to "1". The ldox en and ldo_lsx bits can be found in the ENABLE and LDO LS SELECT registers, respectively.

The device features active discharge. This feature is enabled through the ldox discharge enabled bits. A 100 Ω resistor is connected internally between channel outputs and GND to discharge the output capacitors. The ldo*x*_discharge_enabled bits can be found in the ENABLE register.

To do a global shutdown of all channels, set RESET_B pin to low.

It is not recommended to change configuration from LS to LDO operation while the output is loaded. The channel will attempt a restart and the output may drop significantly. It is recommended to first de−select the channels (with ldo*x*_en bits), de−select *all* ldo_ls*x* bits, then select the channels for LDO operation.

Over−Current Protection (OCP)

The LDOs are protected from short−circuits and excessive loads. When a short−circuit or excessive load condition occurs on an output, the current is limited to the Current Limit value of the LDO and, depending on the difference between input and programmed output voltage, the output voltage may drop. The resultant output voltage is the product of Current Limit and load impedance.

When a current–limit event is detected, the LDOs' associated OCP status bit is set. If the LDO remains in current−limit for 1 ms, the corresponding interrupt bit is set and INT_B asserted low. The LDO will be shutdown and a restarts attempted every 20 ms. Individual LDOs are permanently disabled after four cumulative faults including OCP faults. The LDOs need to be enabled to return to operation.

Multiple Fault Shutdown

To prevent repetitive starting and faulting of an LDO or of the IC itself, detection of four faults will result in a complete shutdown of an LDO or, if system faults, the IC will shutdown.

Individual LDO Fault: the LDO will be shutdown after the fourth fault for any combination of UVLO and/or OCP faults. The LDO will automatically be de−selected and will require enabling to return to operation.

System Fault: all channels will be shutdown after the fourth chip fault for any combination of thermal−shutdown and/or system UVLO faults. All channels will automatically be de−selected. Enabling of the channels will require RESET B pin to be toggled from low to high first.

Reset

When the RESET B pin is pulled LOW, the INTERRUPTx and STATUSx bits will be cleared. All the other registers will remain set to their programmed values, but I²C communication with the device is disabled. Additionally, all internal fault counters will reset to 0.

When the RESET \overline{B} pin is pulled HIGH, the I²C block is turned on. The Reset B pin should not be asserted high while there is data transmission on the $I²C$ bus. This will ensure the FAN53840 doesn't mis-interpret a logic low on SDA as a falling edge and inadvertently create a "Start" condition, and unintended data written to the FAN53840 registers. It is recommended that the FAN53840 is enabled when there is a brief break in $I²C$ data transmissions.

The SOFT RESET bits in the RESET register can be used to clear all registers to their default values.

No Fault Shutdown

When No Fault Shutdown feature is selected, LDOs are prevented from shutting down during an OCP event but are not prevented from shutting down due to a UVLO fault event. When these events occur, the interrupt and status bits will indicate a fault but the fault counter will not be incremented.

This feature is activated by setting no fault shudown bit in RESET register to $"1"$.

I ²C Functionality

I ²C Interface

The FAN53840 serial interface is compatible with Standard, Fast and Fast Plus Mode $I²C$ Bus specifications. The SCL line is an input and its SDA line is a bi−directional open−drain output; it can only pull down the bus when active. The SDA line only pulls LOW during data reads and when signaling ACK. All data is shifted in MSB (bit 7) first.

Please refer to the *Reset* section for guidance on RESET B LOW to HIGH pin timing for proper enabling of the $I²C$ block.

I2C Slave Address

The FAN53840 provides three different $I²C$ addresses. The addresses can be set by connecting the ADDR pin according to the settings in Table 2. Depending on the setting of the ADDR Pin when RESET B is asserted high, the device address will be selected. To reset the address, disable the device by pulling RESET_B low. Reconfigure the ADDR pin to the desired setting then enable the device by asserting RESET_B high.

The $I²C$ is accessible approximately 300 μ s after enabling the device through asserting RESET_B high. For reliable reads of the ADDR pin setting, it is recommended for ADDR pin not to change states during the 300 us detection period. Providing the system power pin voltage does not fall below POR level, register values will be retained while RESET B pin is maintained low.

A precautionary measure: registers should be reprogrammed to desired values anytime a system UVLO fault is detected.

Other default slave addresses can be accommodated by contacting an **onsemi** representative.

Table 2. I2C SLAVE ADDRESS

Bus Timing

As shown in Figure 23, data is normally transferred when SCL is LOW. Data is clocked in on the rising edge of SCL. Typically, data transitions shortly at or after the falling edge of SCL to allow ample time for the data to set up before the next SCL rising edge.

Figure 23. Data Transfer Timing

Each bus transaction begins and ends with SDA and SCL HIGH. A transaction begins with a START condition, which is defined as SDA transitioning from 1 to 0 with SCL HIGH, as shown in Figure [24](#page-18-0).

Transactions end with a STOP condition, which is SDA transitioning from 0 to 1 with SCL HIGH, as shown in Figure 25.

Figure 25. Stop Bit

During a read from the FAN53840, the master issues a Repeated Start after sending the register address and before resending the slave address. The Repeated Start is a 1−to−0 transition on SDA while SCL is HIGH, as shown in Figure 26.

Figure 26. Repeated Start Timing

Figure 28. Single−Byte Read Transaction

Figure 29. Multi−Byte (Sequential) Write Transaction

Read and Write Transactions

The figures below outline the sequences for data read and write. Bus control is signified by the shading of the packet, defined as \Box Master Drives Bus \Box and \Box Slave Drives Bus \Box . All addresses and data are MSB first.

Multi−Byte (Sequential) Read and Write Transactions

Sequential Write (Figure 29)

The Slave Address, Reg Addr address, and the first data byte are transmitted to the FAN53840 in the same way as in a single−byte write (Figure 27). However, instead of generating a Stop condition, the master transmits additional bytes that are written to consecutive sequential registers after the falling edge of the eighth bit. After the last byte written and its ACK bit received, the master issues a STOP bit. The IC contains an 8−bit counter that increments the address pointer after each byte is written.

Sequential Read (Figure 30)

Sequential reads are initiated in the same way as a single−byte read (Figure 28), except that once the slave transmits the first data byte, the master issues an acknowledge instead of a STOP condition. This directs the slave's $I²C$ logic to transmit the next sequentially addressed 8−bit word. The FAN53840 contains an 8−bit counter that increments the address pointer after each byte is read, which allows the entire memory contents to be read during one $I²C$ transaction.

REGISTER MAPPING TABLE

Table 3. REGISTER MAPPING

REGISTER DETAILS

Table 4. REGISTER DETAILS − 0x00 PRODUCT ID

Table 5. REGISTER DETAILS − 0X01 SILICON REV ID

Table 6. REGISTER DETAILS − 0X02 ENABLE

Table 7. REGISTER DETAILS − 0X03 CHAN1

Table [7](#page-22-0). REGISTER DETAILS − 0X03 CHAN1 (continued)

Table 8. REGISTER DETAILS − 0X04 CHAN2

Table [8](#page-24-0). REGISTER DETAILS − 0X04 CHAN2 (continued)

Table 9. REGISTER DETAILS − 0X05 CHAN3

Table [9](#page-26-0). REGISTER DETAILS − 0X05 CHAN3 (continued)

Table 10. REGISTER DETAILS − 0X06 CHAN4

Table [10](#page-28-0). REGISTER DETAILS − 0X06 CHAN4 (continued)

Table 11. REGISTER DETAILS − 0X07 RESET

Table 12. REGISTER DETAILS − 0x08 LDO_COMP0

Table 13. REGISTER DETAILS − 0X09 INTERRUPT1

Table 14. REGISTER DETAILS − 0X0A INTERRUPT2

Table [14](#page-32-0). REGISTER DETAILS − 0X0A INTERRUPT2 (continued)

Table 15. REGISTER DETAILS − 0X0B STATUS1

Table 16. REGISTER DETAILS − 0X0C STATUS2

Table [16.](#page-34-0) REGISTER DETAILS − 0X0C STATUS2 (continued)

Table 17. REGISTER DETAILS − 0X0D STATUS3

Table 18. REGISTER DETAILS − 0X0E MINT1

Table 19. REGISTER DETAILS − 0X0F MINT2

Table [19.](#page-36-0) REGISTER DETAILS − 0X0F MINT2 (continued)

Table 20. REGISTER DETAILS − 0X10 LDO_LS_SELECT

APPLICATION GUIDELINES

LDO Input Capacitor Considerations

If long wires are used to bring power to an evaluation board, additional "bulk" capacitance should be placed on the evaluation board between the local input capacitor(s)and the power source lead(s) to reduce ringing caused by inductance lead length. Use only X5R and X7R ceramic capacitorswith adequate voltage rating for local input capacitors.

The effective capacitance value decreases as the voltage across the capacitor increases due to DC bias effects. Adding additional capacitance to the minimum recommended ensures reliable operation.

LDO Output Capacitor Considerations

FAN53840 LDOs are initially set at the factory for a range of 4.7μ F to 10μ F (unbiased) on LDO1. LDO2/3/4 are initially set for a range of 1μ F to 4.7μ F (unbiased). All LDOs can be trimmed at the factory for up to 47μ F total (unbiased) capacitance. When evaluating and ordering the FAN53840, to ensure optimum performance and stability, specify the amount of capacitance each LDO output will have with an **onsemi** representative.

Use only X5R and X7R ceramic capacitors with adequate voltage rating for the output capacitors.

PCB Layout Recommendations

Local input and output capacitors should be placed close to the corresponding input and output pins. The ground terminal of the capacitors should be connected to a good ground plane − preferably on the surface of the board. Input power should be routed to the input capacitor first, then to the input pin(s) of the IC. Power from layers other than the layer on which a capacitor sits, should be routed to the capacitor layer with vias close to the positive terminal of the capacitor. Power traces from outputs should be routed to the output capacitor first, then to other layers if necessary.

Figure 31. Recommended PCB Assembly (Top View)

Figure 32. Recommended PCB Layout

MAX.

0.473

0.194

 0.251

0.028

 0.251

 1.55

1.55

0.250

0.250

WLCSP16 1.52x1.52x0.432 CASE 567ZM ISSUE O DATE 14 SEP 2020 NOTES: 0.03 C \bigcirc A 1. DIMENSIONING AND TOLERANCING PER |B | $2X$ ASME Y14.5M, 2009. 2. CONTROLLING DIMENSION: MILLIMETERS 3. DATUM C IS DEFINED BY THE SPHERICAL **CROWNS OF THE SOLDER BALLS BALLA1** D **INDEX AREA MILLIMETERS** 0.03 C \bigcirc **DIM** MIN. NOM. $2X$ 0.391 0.432 **TOP VIEW** A 0.154 $A₁$ 0.174 **BACKSIDE COATING** A3 $A2$ 0.215 0.233 A₂ A3 0.022 0.025 //|0.06 C 0.211 0.231 $\mathsf b$ \Box 0.05 | C $A₁$ 1.49 1.52 D A E 1.49 1.52 ╔ **DETAIL A** 0.35 BSC $\mathsf{e}% _{t}\left(t\right)$ **SEATING PLANE** 0.220 0.235 x **SIDE VIEW** 0.220 0.235 y \varnothing b $\overline{\bigoplus}$ 0.005 $\overline{\omega}$ C A B le (Ø0.200)Bottom le $16X$ of Cu Pad $A1$ ⊕⊕¦೦೦ D \oplus \oplus \oplus e 0000 $\mathsf C$ e 0000 $\overline{\oplus}$ olo $\overline{\oplus}$ B $-\oplus$ \circ \circ ⊕ O'O ⊕ Θ O O O RECOMMENDED $1 \quad 2 \quad 3$ (y) MOUNTING FOOTPRINT* (x) (NSMD PAD TYPE) *FOR ADDITIONAL INFORMATION ON OUR Pb-FREE
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TECHNIQUES REFERENCE MANUAL, SOLDERIM/D. **BOTTOM VIEW**

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